

# ELECTRONIC INFORMATION DISCLOSURE STATEMENT

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## Title of Invention

TFI PROBE I/O WRAP TEST METHOD

Application Number :

Confirmation Number:

First Named Applicant: Gobinda Das

Attorney Docket Number: 21806-00146-US1

Art Unit: 2829

Examiner: E. F. Karlsen

Search string: ( 4968931 or 5968191 or 6323663 or 5887001 or 5852617 or 5787098 or 5450415 or 5416409 or 5390191 or 5321277 or 5207885 or 4967142 or 3867693 or 4241307 or 5491427 or 5909124 ).pn

## US Patent Documents

**Note: Applicant is not required to submit a paper copy of cited US Patent Documents**

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	AA	4968931	1990-11-01	Littlebury, et al.			
	AB	5968191	1999-10-01	Thatcher, et al.			
	AC	6323663	2001-11-01	Nakata, et al.			
	AD	5887001	1999-03-23	Russell			
	AE	5852617	1998-12-22	Mote, Jr.			
	AF	5787098	1998-07-28	DasGupta, et al.			
	AG	5450415	1995-09-12	Kamada			
	AH	5416409	1995-05-16	Hunter			
	AI	5390191	1995-02-14	Shiono, et al.			
	AJ	5321277	1994-06-14	Sparks, et al.			
	AK	5207885	1993-05-04	Byrnes, et al.			
	AL	4967142	1990-10-30	Sauerwald, et al.			
	AM	3867693	1975-02-01	Saxenmeyer, Sr.			
	AN	4241307	1980-12-01	Hong			
	AO	5491427	1996-02-01	Ueno, et al.			
	AP	5909124	1999-06-01	Madine, et al.			

## Signature

Examiner Name	Date